high-performance controller for embedded test and programming
outstanding flexibility through multifunctional I/O channels and FPGA instrumentation for mixed-signal and high-speed test
high modularity and scalability through configurable TAP interface cards and additional I/O modules
integrated compact unit controllable via USB 3.0 and GBit LAN
Parameters

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Details</th>
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<tbody>
<tr>
<td>number of TAP slots</td>
<td>4 (independent and individually configurable with TAP plug-in card)</td>
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<tr>
<td>maximum TCK frequency</td>
<td>20/50/100 MHz (adjustable via software)</td>
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<tr>
<td>parallel I/O channels</td>
<td>64 mixed-signal channels combined with FPGA, individually configurable as Input, Output, Tri-State, via software programmable V&lt;sub&gt;1&lt;/sub&gt; 0.9-3.6 V (8 groups with 8 I/O)</td>
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<tr>
<td>maximum number of I/O modules</td>
<td>30 modules via external SFX carrier</td>
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<tr>
<td>integrated technologies</td>
<td>SPACE™, HYSCAN™, ADYCS™, ChipVORX®, FastScale™</td>
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Embedded test

- support of latest technologies such as Processor Emulation Test, FPGA Assisted Test and Embedded Diagnostics Test
- synchronization with multifunctional I/O channels and ChipVORX® FPGA instruments

Embedded programming

- high-speed programming of Flash components like NAND, NOR, SPI, FC, eMMC etc. (also via I/O)
- universal programming of microcontrollers
- FPGA/PLD programming

Expandability

- support of up to 30 parallel controlled SCANFLEX® I/O modules
- scalable number of one to four TAPs
- interfaces for additional debug and control components

Adaptability

- transmission over long distances of up to four meter to the target without TCK reduction or transmission problems
- software-parameterized I/O (slew rate, impedance, termination)
- via software selectable protocols (JTAG, DAP, COP, SWD, BDM, SBW, UART etc.)

High performance

- use of powerful multi-core processors and FPGAs
- simultaneous operation at up to 100 MHz on all TAPs
- operation at up to 100 MHz on I/O channels
- support for gang operations

Software

- integrated into Embedded JTAG Solutions platform SYSTEM CASCON™
- Plug and Play integration in 3rd party systems
- open mix of test and programming procedures in one software environment

Technical specification

SCANFLEX® II BLADE 4
Flexible controller for embedded test and programming

ISO 9001 certified

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Scanflex II BLADE 4/E/10-2018

Made in Germany